

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#6
2/17/00
Murphy

In re Application of:

Date: June 30, 1999

B. Beaman et. al.

Group Art Unit: 2858

Serial No.: 09/088,394

Examiner: V. Nguyen

Filed: June 1, 1998

Docket No: YO993-028AB

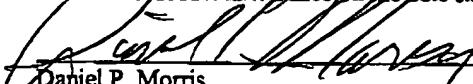
For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS,
TEST PROBE AND METHODS OF USE THEREOF

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Assistant Commissioner for Patents
Washington, D. C. 20231

FEB 14 2000

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I hereby certify that this paper is being facsimile transmitted under Rule CFR 1.61(d) to the U.S.
Patent and Trademark Office on the date shown above.
Daniel P. Morris
Reg. No. 32,053Response

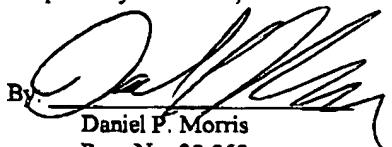
In response to Office Action dated July 1, 1999, please consider the following:

REMARKS

Applicants elect Group I, claims 6-19 and 22-24 without traverse.

Respectfully submitted,

By:


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** TOTAL PAGE.02 **